

**Search Notes**

Application/Control No.

10/564,894

Examiner

Hai H. Huynh

Applicant(s)/Patent under  
Reexamination

MORIYA ET AL.

Art Unit

3747

**SEARCHED**

Class	Subclass	Date	Examiner
123	299	8/23/2006	HHH
123	300	8/23/2006	HHH
123	305	8/23/2006	HHH
123	406.22	8/23/2006	HHH
123	406.26	8/23/2006	HHH
123	435	8/23/2006	HHH
123	90.15	8/23/2006	HHH
701	103-105	8/23/2006	HHH
701	111	8/23/2006	HHH
73	117.3	8/23/2006	HHH
73	118.1	8/23/2006	HHH
update	search	2/28/2007	HHH
		6/20/2007	HHH

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East	8/23/2006	HHH
	2/28/2007	HHH
	6/20/2007	HHH